

Resource Summary Report

Generated by [NIF](#) on Sep 23, 2026

FEI: Quattro ESEM

RRID:SCR_019901

Type: Tool

Proper Citation

FEI: Quattro ESEM (RRID:SCR_019901)

Resource Information

URL: <https://www.fei.com/products/sem/quattro-for-materials-science/>

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Description: Scanning electron microscope that combines a field emission gun (FEG) and three vacuum modes (high vacuum, low vacuum, and ESEM) to provide the flexibility to accommodate a wide range of samples, including those that are outgassing or otherwise not vacuum-compatible.

Resource Type: instrument resource

Keywords: FEI, SEM, Instrument Equipment, USEDit, Environmental Scanning Electron Microscope, electron microscope,

Availability: Commercially available

Resource Name: FEI: Quattro ESEM

Resource ID: SCR_019901

Alternate IDs: Model_Number_Quattro_ESEM

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260919T195421+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Quattro ESEM.

No alerts have been found for FEI: Quattro ESEM.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.